www.SeCosGmbH.com

Headquarter Address:
8F.No.33, Lane 155, Sec.3, Bei-Shen Rd.,
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Product/Process Change Notification

PCN#	Effective Date	Issue Date
2014-06-01C-01	2014/9/1	2014/6/1

PCN Classification	Product Category
Major	HER207G

Subject

Add assembly vendor

Affected Product(s)

HER207G

Description of Change(s)

In order to avoid shortage of the material, and enhance the speed of delivery, thus, we add a new assembly house.

Content of Change(s)

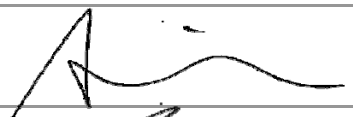
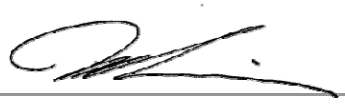
Packing change, the original packaging quantity is 3Kpce, now change the packaging quantity is 1.8Kpcs

Impact(s)

None

Attachment(s)

Reliability Test Report. SGS report. Package Information.

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website http://www.secosgmbh.com

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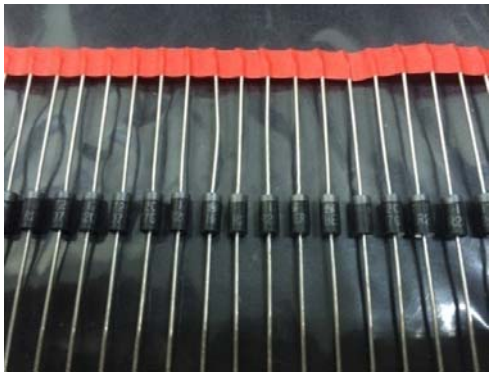
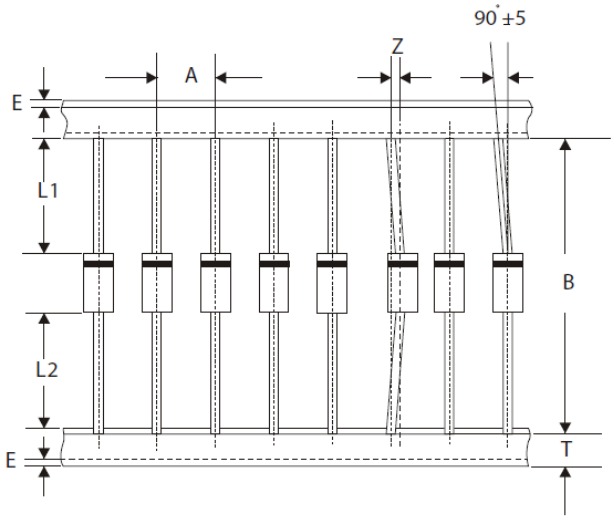
Exterior comparison Chart	
Original	New
	
Top View	Top View
	
Lateral View	Lateral View
	
Reel	Reel

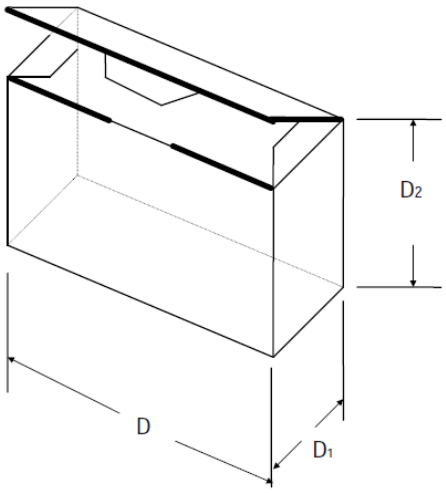
Elektronische Bauelemente

Packaging Information
Axial Lead Devices
Ammunition Taping Specification

DO-15 / DO-27 / DO-41 / R-1

Component Outline	Component Pitch A	Inner Tape Pitch B	
		52mm	26mm
DO-15	5.0mm±0.5mm	52.4±1.5mm	-
DO-27	10mm±0.5mm	52.4±1.5mm	-
DO-41	5.0mm±0.5mm	52.4±1.5mm	26.5±0.4mm
R-1	5.0 mm±0.3mm	-	26.5±0.4mm





Component Outline	Item	Symbol	Specification(mm)	
			52mm	26mm
DO-15	Component Alignment	Z	1.0 MAX	-
DO-27			1.2 MAX	-
DO-41			1.0 MAX	1.0 MAX
R-1			-	0.5 MAX
DO-15 / DO-27/ DO-41/ R-1	Tape Width	T	6.0±0.5	6.0±0.5
DO-15	Exposed Adhesive	E	0.8 MAX	-
DO-27			0.5 MAX	-
DO-41			0.8 MAX	0.8 MAX
R-1			-	0.5 MAX
DO-15	Body Eccentricity	lL1-L2l	0±1.0	-
DO-27			0±1.0	-
DO-41			0±1.0	0±0.5
R-1			-	0±0.5
DO-15 / DO-27/ DO-41/ R-1	Reel Outside diameter	D	255mm	255mm
DO-15 / DO-27/ DO-41/ R-1	Reel inner diameter	D1	80mm	80mm
DO-15 / DO-27/ DO-41/ R-1	Reel hole diameter	D2	92mm	92mm

Note:

When using the tape to stick the component, both ends of the tape should be stick at the lower side of the component. Cut it flat and compress the tape to prevent it curled. For each reel, the tape cannot be stick more than two place and each taped area should not less than 10cm.

SeCoS Corporation

Reliability Testing Summary Report

Date: 2014/04/30 Document No.: SH14 -04- 22

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	HER207G	100 ± 5℃, 80%VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	HER207G	150℃, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	HER207G	121℃, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	HER207G	-55℃/30min, 150℃/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	HER207G	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	HER207G	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
Solder Resistance DITY	HER207G	270±5℃, 7Sec ＋2/－0 Sec		10	0	0	ACC

Judgment:

■ **qualified** □ **unqualified**

Testing Start Date: 2014.03.03 Testing End Date: 2014.04.30

Tester: Leo Hsia Approval: Peter Yang

SeCoS Corporation

Electrical Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 25℃
Test Date: 2014.03.03 ~ 2014.03.03
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	IR (uA)
1	1474mV	0.174uA
2	1402mV	0.247uA
3	1439mV	0.220uA
4	1361mV	0.133uA
5	1378mV	0.184uA
6	1321mV	0.228uA
7	1433mV	0.204uA
8	1427mV	0.268uA
9	1314mV	0.147uA
10	1505mV	0.226uA
11	1512mV	0.168uA
12	1523mV	0.266uA
13	1519mV	0.075uA
14	1483mV	0.129uA
15	1424mV	0.078uA
16	1421mV	0.152uA
17	1422mV	0.109uA
18	1416mV	0.277uA
19	1355mV	0.207uA
20	1312mV	0.100uA
21	1518mV	0.170uA
22	1429mV	0.239uA
23	1323mV	0.283uA
24	1370mV	0.160uA
25	1421mV	0.161uA
26	1342mV	0.163uA
27	1335mV	0.258uA
28	1376mV	0.196uA
29	1468mV	0.307uA
30	1360mV	0.275uA
31	1388mV	0.110uA

SeCoS Corporation

Electrical Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 25℃
Test Date: 2014.03.03 ~ 2014.03.03
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	IR (uA)
32	1429mV	0.306uA
33	1512mV	0.268uA
34	1493mV	0.281uA
35	1320mV	0.215uA
36	1297mV	0.059uA
37	1479mV	0.088uA
38	1447mV	0.102uA
39	1404mV	0.131uA
40	1318mV	0.046uA
41	1392mV	0.272uA
42	1479mV	0.275uA
43	1361mV	0.274uA
44	1432mV	0.159uA
45	1295mV	0.274uA
46	1401mV	0.204uA
47	1493mV	0.184uA
48	1358mV	0.135uA
49	1321mV	0.242uA
50	1306mV	0.124uA
51	1435mV	0.149uA
52	1298mV	0.298uA
53	1352mV	0.050uA
54	1454mV	0.143uA
55	1464mV	0.185uA
56	1508mV	0.146uA
57	1520mV	0.047uA
58	1380mV	0.247uA
59	1299mV	0.225uA
60	1430mV	0.098uA
61	1473mV	0.245uA
62	1387mV	0.154uA

SeCoS Corporation

Electrical Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 25℃
Test Date: 2014.03.03 ~ 2014.03.03
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	IR (uA)
63	1416mV	0.212uA
64	1507mV	0.117uA
65	1327mV	0.242uA
66	1515mV	0.296uA
67	1467mV	0.239uA
68	1374mV	0.239uA
69	1329mV	0.183uA
70	1447mV	0.097uA
71	1317mV	0.113uA
72	1433mV	0.165uA
73	1314mV	0.263uA
74	1388mV	0.094uA
75	1498mV	0.234uA
76	1432mV	0.272uA
77	1428mV	0.222uA

Made By: Leo Hsia Approval: Peter Yang

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2014.03.03 ~ 2014.04.15
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	1388mV	0.195uA	1457mV	0.047uA
2	1390mV	0.059uA	1406mV	0.122uA
3	1463mV	0.238uA	1427mV	0.265uA
4	1362mV	0.087uA	1333mV	0.232uA
5	1417mV	0.229uA	1369mV	0.270uA
6	1420mV	0.061uA	1453mV	0.052uA
7	1488mV	0.258uA	1317mV	0.279uA
8	1377mV	0.161uA	1497mV	0.302uA
9	1403mV	0.243uA	1359mV	0.277uA
10	1451mV	0.110uA	1400mV	0.170uA
11	1495mV	0.150uA	1448mV	0.190uA
12	1490mV	0.285uA	1452mV	0.075uA
13	1461mV	0.239uA	1503mV	0.271uA
14	1463mV	0.184uA	1421mV	0.097uA
15	1301mV	0.178uA	1382mV	0.229uA
16	1430mV	0.209uA	1456mV	0.175uA
17	1423mV	0.191uA	1346mV	0.201uA
18	1495mV	0.165uA	1399mV	0.133uA
19	1431mV	0.091uA	1492mV	0.233uA
20	1306mV	0.119uA	1402mV	0.219uA
21	1296mV	0.131uA	1324mV	0.119uA
22	1317mV	0.206uA	1491mV	0.152uA
23	1376mV	0.191uA	1326mV	0.185uA
24	1369mV	0.147uA	1476mV	0.184uA
25	1368mV	0.273uA	1408mV	0.272uA
26	1374mV	0.145uA	1486mV	0.179uA
27	1456mV	0.241uA	1302mV	0.169uA
28	1492mV	0.286uA	1335mV	0.187uA
29	1380mV	0.066uA	1361mV	0.274uA
30	1372mV	0.251uA	1314mV	0.053uA

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2014.03.03 ~ 2014.04.15
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
31	1514mV	0.104uA	1392mV	0.144uA
32	1377mV	0.236uA	1455mV	0.124uA
33	1407mV	0.150uA	1392mV	0.170uA
34	1360mV	0.072uA	1436mV	0.104uA
35	1345mV	0.114uA	1333mV	0.265uA
36	1482mV	0.234uA	1333mV	0.180uA
37	1471mV	0.084uA	1509mV	0.168uA
38	1355mV	0.196uA	1292mV	0.239uA
39	1479mV	0.249uA	1301mV	0.246uA
40	1354mV	0.280uA	1320mV	0.244uA
41	1493mV	0.139uA	1410mV	0.073uA
42	1518mV	0.197uA	1297mV	0.245uA
43	1318mV	0.109uA	1421mV	0.223uA
44	1517mV	0.102uA	1354mV	0.079uA
45	1319mV	0.047uA	1412mV	0.268uA
46	1380mV	0.249uA	1385mV	0.104uA
47	1410mV	0.303uA	1465mV	0.180uA
48	1410mV	0.130uA	1445mV	0.113uA
49	1462mV	0.140uA	1359mV	0.277uA
50	1509mV	0.056uA	1332mV	0.091uA
51	1461mV	0.258uA	1330mV	0.235uA
52	1479mV	0.183uA	1481mV	0.135uA
53	1485mV	0.180uA	1330mV	0.197uA
54	1423mV	0.050uA	1437mV	0.103uA
55	1515mV	0.159uA	1511mV	0.170uA
56	1400mV	0.134uA	1358mV	0.181uA
57	1356mV	0.169uA	1368mV	0.077uA
58	1375mV	0.088uA	1466mV	0.186uA
59	1308mV	0.128uA	1396mV	0.157uA
60	1470mV	0.283uA	1363mV	0.276uA

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 100 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2014.03.03 ~ 2014.04.15
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
61	1502mV	0.062uA	1427mV	0.262uA
62	1521mV	0.230uA	1380mV	0.088uA
63	1476mV	0.251uA	1357mV	0.110uA
64	1378mV	0.139uA	1417mV	0.070uA
65	1481mV	0.301uA	1423mV	0.126uA
66	1429mV	0.233uA	1410mV	0.270uA
67	1476mV	0.051uA	1446mV	0.177uA
68	1400mV	0.256uA	1321mV	0.255uA
69	1351mV	0.091uA	1388mV	0.088uA
70	1436mV	0.095uA	1380mV	0.220uA
71	1429mV	0.296uA	1451mV	0.111uA
72	1438mV	0.267uA	1516mV	0.191uA
73	1324mV	0.058uA	1470mV	0.270uA
74	1419mV	0.308uA	1424mV	0.053uA
75	1473mV	0.217uA	1377mV	0.102uA
76	1424mV	0.295uA	1348mV	0.303uA
77	1377mV	0.228uA	1513mV	0.233uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 150℃, 1000Hrs
Test Date: 2014.03.03 ~ 2014.04.15
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	1389mV	0.201uA	1501mV	0.253uA
2	1301mV	0.083uA	1508mV	0.179uA
3	1438mV	0.200uA	1361mV	0.276uA
4	1325mV	0.281uA	1301mV	0.112uA
5	1388mV	0.243uA	1378mV	0.049uA
6	1451mV	0.167uA	1516mV	0.143uA
7	1314mV	0.082uA	1331mV	0.258uA
8	1381mV	0.094uA	1405mV	0.291uA
9	1446mV	0.287uA	1459mV	0.164uA
10	1481mV	0.074uA	1398mV	0.244uA
11	1410mV	0.048uA	1305mV	0.276uA
12	1444mV	0.274uA	1370mV	0.155uA
13	1298mV	0.230uA	1406mV	0.306uA
14	1455mV	0.165uA	1474mV	0.229uA
15	1497mV	0.301uA	1512mV	0.226uA
16	1450mV	0.254uA	1399mV	0.057uA
17	1329mV	0.091uA	1452mV	0.077uA
18	1385mV	0.100uA	1357mV	0.178uA
19	1523mV	0.179uA	1359mV	0.177uA
20	1503mV	0.241uA	1518mV	0.108uA
21	1476mV	0.283uA	1360mV	0.226uA
22	1409mV	0.218uA	1349mV	0.198uA
23	1464mV	0.096uA	1407mV	0.081uA
24	1478mV	0.137uA	1325mV	0.063uA
25	1384mV	0.184uA	1465mV	0.094uA
26	1360mV	0.303uA	1500mV	0.127uA
27	1396mV	0.286uA	1315mV	0.294uA
28	1298mV	0.266uA	1464mV	0.185uA
29	1522mV	0.229uA	1378mV	0.251uA
30	1458mV	0.171uA	1378mV	0.150uA

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 150℃, 1000Hrs
Test Date: 2014.03.03 ~ 2014.04.15
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
31	1374mV	0.076uA	1291mV	0.202uA
32	1334mV	0.178uA	1413mV	0.223uA
33	1303mV	0.186uA	1497mV	0.249uA
34	1497mV	0.154uA	1334mV	0.270uA
35	1369mV	0.193uA	1307mV	0.111uA
36	1304mV	0.231uA	1342mV	0.184uA
37	1309mV	0.220uA	1298mV	0.060uA
38	1337mV	0.046uA	1517mV	0.151uA
39	1403mV	0.268uA	1368mV	0.074uA
40	1327mV	0.186uA	1458mV	0.184uA
41	1442mV	0.153uA	1445mV	0.075uA
42	1414mV	0.073uA	1362mV	0.225uA
43	1470mV	0.060uA	1517mV	0.072uA
44	1412mV	0.302uA	1370mV	0.243uA
45	1472mV	0.262uA	1307mV	0.055uA
46	1471mV	0.054uA	1517mV	0.147uA
47	1410mV	0.128uA	1469mV	0.072uA
48	1452mV	0.234uA	1498mV	0.302uA
49	1346mV	0.236uA	1291mV	0.304uA
50	1506mV	0.178uA	1404mV	0.213uA
51	1384mV	0.248uA	1462mV	0.305uA
52	1329mV	0.182uA	1403mV	0.283uA
53	1422mV	0.230uA	1513mV	0.175uA
54	1443mV	0.173uA	1462mV	0.193uA
55	1418mV	0.272uA	1301mV	0.248uA
56	1377mV	0.232uA	1452mV	0.219uA
57	1502mV	0.066uA	1348mV	0.190uA
58	1484mV	0.146uA	1329mV	0.061uA
59	1364mV	0.160uA	1350mV	0.242uA
60	1358mV	0.100uA	1442mV	0.106uA

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 150℃, 1000Hrs
Test Date: 2014.03.03 ~ 2014.04.15
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
61	1484mV	0.292uA	1457mV	0.116uA
62	1438mV	0.217uA	1473mV	0.275uA
63	1332mV	0.100uA	1368mV	0.231uA
64	1491mV	0.128uA	1377mV	0.071uA
65	1326mV	0.076uA	1502mV	0.137uA
66	1320mV	0.176uA	1467mV	0.199uA
67	1447mV	0.202uA	1452mV	0.258uA
68	1331mV	0.128uA	1479mV	0.124uA
69	1397mV	0.142uA	1341mV	0.301uA
70	1392mV	0.138uA	1364mV	0.186uA
71	1375mV	0.149uA	1428mV	0.230uA
72	1515mV	0.086uA	1433mV	0.045uA
73	1403mV	0.089uA	1365mV	0.051uA
74	1414mV	0.250uA	1456mV	0.303uA
75	1483mV	0.059uA	1410mV	0.195uA
76	1372mV	0.304uA	1476mV	0.256uA
77	1401mV	0.077uA	1408mV	0.082uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

Pressure Cooker Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2014.03.03 ~ 2014.03.11
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	1413mV	0.155uA	1339mV	0.059uA
2	1436mV	0.300uA	1428mV	0.260uA
3	1473mV	0.161uA	1439mV	0.056uA
4	1363mV	0.150uA	1356mV	0.189uA
5	1460mV	0.311uA	1378mV	0.223uA
6	1505mV	0.191uA	1407mV	0.056uA
7	1477mV	0.099uA	1463mV	0.256uA
8	1426mV	0.220uA	1419mV	0.093uA
9	1451mV	0.292uA	1303mV	0.269uA
10	1419mV	0.206uA	1374mV	0.256uA
11	1374mV	0.109uA	1381mV	0.046uA
12	1336mV	0.188uA	1464mV	0.238uA
13	1503mV	0.095uA	1379mV	0.161uA
14	1430mV	0.081uA	1467mV	0.054uA
15	1463mV	0.085uA	1512mV	0.230uA
16	1347mV	0.124uA	1453mV	0.201uA
17	1449mV	0.160uA	1509mV	0.186uA
18	1417mV	0.069uA	1292mV	0.051uA
19	1339mV	0.110uA	1303mV	0.230uA
20	1433mV	0.096uA	1437mV	0.147uA
21	1335mV	0.052uA	1487mV	0.262uA
22	1476mV	0.228uA	1350mV	0.283uA
23	1415mV	0.180uA	1443mV	0.174uA
24	1405mV	0.060uA	1509mV	0.239uA
25	1328mV	0.216uA	1378mV	0.096uA
26	1469mV	0.137uA	1500mV	0.289uA
27	1384mV	0.084uA	1421mV	0.183uA
28	1387mV	0.235uA	1416mV	0.053uA
29	1457mV	0.179uA	1430mV	0.269uA
30	1479mV	0.134uA	1400mV	0.056uA

SeCoS Corporation

Pressure Cooker Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2014.03.03 ~ 2014.03.11
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
31	1469mV	0.186uA	1384mV	0.261uA
32	1336mV	0.269uA	1390mV	0.112uA
33	1379mV	0.253uA	1386mV	0.112uA
34	1389mV	0.215uA	1440mV	0.155uA
35	1304mV	0.071uA	1470mV	0.089uA
36	1477mV	0.173uA	1406mV	0.104uA
37	1459mV	0.248uA	1472mV	0.119uA
38	1475mV	0.204uA	1398mV	0.188uA
39	1365mV	0.106uA	1496mV	0.128uA
40	1337mV	0.293uA	1297mV	0.113uA
41	1457mV	0.272uA	1426mV	0.068uA
42	1508mV	0.110uA	1472mV	0.157uA
43	1424mV	0.135uA	1391mV	0.067uA
44	1446mV	0.058uA	1296mV	0.051uA
45	1333mV	0.132uA	1304mV	0.118uA
46	1344mV	0.176uA	1479mV	0.115uA
47	1351mV	0.234uA	1413mV	0.143uA
48	1486mV	0.286uA	1412mV	0.075uA
49	1367mV	0.218uA	1333mV	0.061uA
50	1455mV	0.257uA	1423mV	0.311uA
51	1336mV	0.140uA	1367mV	0.198uA
52	1440mV	0.054uA	1293mV	0.137uA
53	1315mV	0.165uA	1390mV	0.094uA
54	1382mV	0.194uA	1503mV	0.250uA
55	1314mV	0.080uA	1401mV	0.309uA
56	1369mV	0.271uA	1373mV	0.077uA
57	1400mV	0.211uA	1402mV	0.247uA
58	1333mV	0.172uA	1442mV	0.282uA
59	1377mV	0.123uA	1387mV	0.114uA
60	1411mV	0.072uA	1392mV	0.077uA

SeCoS Corporation

Pressure Cooker Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2014.03.03 ~ 2014.03.11
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
61	1366mV	0.175uA	1339mV	0.221uA
62	1455mV	0.098uA	1440mV	0.166uA
63	1500mV	0.133uA	1469mV	0.112uA
64	1334mV	0.273uA	1320mV	0.218uA
65	1504mV	0.211uA	1414mV	0.114uA
66	1509mV	0.048uA	1410mV	0.139uA
67	1422mV	0.103uA	1389mV	0.291uA
68	1397mV	0.158uA	1402mV	0.142uA
69	1459mV	0.279uA	1492mV	0.296uA
70	1480mV	0.308uA	1465mV	0.062uA
71	1453mV	0.119uA	1435mV	0.158uA
72	1425mV	0.054uA	1519mV	0.225uA
73	1467mV	0.172uA	1434mV	0.219uA
74	1463mV	0.070uA	1318mV	0.228uA
75	1341mV	0.085uA	1349mV	0.112uA
76	1460mV	0.307uA	1504mV	0.250uA
77	1362mV	0.163uA	1460mV	0.291uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

Temperature Cycle Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2014.03.03 ~ 2014.04.25
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	1428mV	0.275uA	1445mV	0.188uA
2	1481mV	0.083uA	1351mV	0.130uA
3	1431mV	0.079uA	1499mV	0.143uA
4	1522mV	0.050uA	1290mV	0.209uA
5	1343mV	0.155uA	1337mV	0.093uA
6	1341mV	0.183uA	1458mV	0.135uA
7	1355mV	0.189uA	1392mV	0.070uA
8	1425mV	0.280uA	1390mV	0.311uA
9	1404mV	0.086uA	1405mV	0.161uA
10	1322mV	0.294uA	1342mV	0.098uA
11	1404mV	0.118uA	1407mV	0.213uA
12	1413mV	0.064uA	1461mV	0.097uA
13	1369mV	0.053uA	1436mV	0.113uA
14	1467mV	0.078uA	1313mV	0.077uA
15	1417mV	0.234uA	1460mV	0.113uA
16	1414mV	0.063uA	1313mV	0.071uA
17	1408mV	0.067uA	1394mV	0.230uA
18	1448mV	0.079uA	1348mV	0.292uA
19	1493mV	0.112uA	1495mV	0.088uA
20	1334mV	0.251uA	1514mV	0.076uA
21	1475mV	0.072uA	1361mV	0.213uA
22	1322mV	0.195uA	1433mV	0.202uA
23	1366mV	0.163uA	1390mV	0.062uA
24	1416mV	0.217uA	1429mV	0.103uA
25	1479mV	0.266uA	1340mV	0.174uA
26	1326mV	0.215uA	1339mV	0.198uA
27	1348mV	0.172uA	1475mV	0.142uA
28	1518mV	0.254uA	1386mV	0.199uA
29	1440mV	0.215uA	1393mV	0.310uA
30	1411mV	0.099uA	1443mV	0.106uA

SeCoS Corporation

Temperature Cycle Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2014.03.03 ~ 2014.04.25
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
31	1435mV	0.217uA	1330mV	0.153uA
32	1508mV	0.063uA	1344mV	0.276uA
33	1433mV	0.119uA	1343mV	0.111uA
34	1482mV	0.220uA	1473mV	0.060uA
35	1434mV	0.263uA	1518mV	0.266uA
36	1479mV	0.255uA	1327mV	0.169uA
37	1409mV	0.137uA	1363mV	0.090uA
38	1331mV	0.073uA	1412mV	0.291uA
39	1326mV	0.287uA	1514mV	0.055uA
40	1339mV	0.062uA	1439mV	0.081uA
41	1322mV	0.300uA	1306mV	0.212uA
42	1319mV	0.103uA	1488mV	0.136uA
43	1444mV	0.128uA	1455mV	0.078uA
44	1321mV	0.246uA	1332mV	0.272uA
45	1491mV	0.257uA	1508mV	0.232uA
46	1500mV	0.226uA	1389mV	0.203uA
47	1449mV	0.171uA	1456mV	0.096uA
48	1291mV	0.102uA	1401mV	0.229uA
49	1493mV	0.131uA	1339mV	0.276uA
50	1506mV	0.092uA	1317mV	0.247uA
51	1335mV	0.087uA	1452mV	0.306uA
52	1386mV	0.066uA	1370mV	0.179uA
53	1474mV	0.249uA	1491mV	0.286uA
54	1421mV	0.286uA	1469mV	0.133uA
55	1392mV	0.298uA	1459mV	0.246uA
56	1515mV	0.272uA	1330mV	0.058uA
57	1382mV	0.095uA	1444mV	0.212uA
58	1507mV	0.073uA	1359mV	0.257uA
59	1406mV	0.237uA	1450mV	0.139uA
60	1399mV	0.203uA	1504mV	0.062uA

SeCoS Corporation

Temperature Cycle Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2014.03.03 ~ 2014.04.25
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
61	1450mV	0.197uA	1451mV	0.167uA
62	1391mV	0.303uA	1346mV	0.251uA
63	1335mV	0.229uA	1503mV	0.125uA
64	1370mV	0.298uA	1391mV	0.239uA
65	1321mV	0.205uA	1441mV	0.168uA
66	1378mV	0.263uA	1366mV	0.177uA
67	1351mV	0.139uA	1372mV	0.122uA
68	1385mV	0.295uA	1434mV	0.185uA
69	1470mV	0.154uA	1505mV	0.227uA
70	1305mV	0.261uA	1461mV	0.062uA
71	1428mV	0.092uA	1456mV	0.276uA
72	1440mV	0.180uA	1417mV	0.219uA
73	1408mV	0.061uA	1483mV	0.135uA
74	1418mV	0.228uA	1295mV	0.272uA
75	1365mV	0.077uA	1431mV	0.172uA
76	1341mV	0.128uA	1399mV	0.220uA
77	1369mV	0.140uA	1440mV	0.175uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.03.11 ~ 2014.04.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	1473mV	0.185uA	1475mV	0.055uA
2	1363mV	0.277uA	1412mV	0.213uA
3	1434mV	0.112uA	1328mV	0.286uA
4	1499mV	0.273uA	1508mV	0.247uA
5	1361mV	0.064uA	1337mV	0.169uA
6	1302mV	0.085uA	1326mV	0.049uA
7	1496mV	0.303uA	1436mV	0.287uA
8	1462mV	0.136uA	1323mV	0.298uA
9	1391mV	0.254uA	1316mV	0.223uA
10	1400mV	0.189uA	1355mV	0.297uA
11	1403mV	0.050uA	1348mV	0.130uA
12	1493mV	0.234uA	1458mV	0.164uA
13	1414mV	0.226uA	1497mV	0.255uA
14	1428mV	0.101uA	1402mV	0.257uA
15	1407mV	0.242uA	1376mV	0.272uA
16	1431mV	0.279uA	1341mV	0.184uA
17	1405mV	0.045uA	1429mV	0.176uA
18	1339mV	0.237uA	1443mV	0.270uA
19	1463mV	0.139uA	1434mV	0.277uA
20	1332mV	0.302uA	1327mV	0.100uA
21	1316mV	0.092uA	1429mV	0.190uA
22	1364mV	0.047uA	1334mV	0.310uA
23	1388mV	0.054uA	1399mV	0.114uA
24	1355mV	0.254uA	1400mV	0.224uA
25	1444mV	0.091uA	1395mV	0.063uA
26	1451mV	0.203uA	1418mV	0.101uA
27	1395mV	0.095uA	1479mV	0.221uA
28	1510mV	0.159uA	1292mV	0.161uA
29	1420mV	0.275uA	1437mV	0.215uA
30	1471mV	0.273uA	1359mV	0.283uA

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.03.11 ~ 2014.04.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
31	1401mV	0.222uA	1337mV	0.212uA
32	1497mV	0.291uA	1458mV	0.111uA
33	1387mV	0.285uA	1401mV	0.173uA
34	1432mV	0.156uA	1374mV	0.239uA
35	1410mV	0.123uA	1384mV	0.202uA
36	1431mV	0.155uA	1361mV	0.246uA
37	1347mV	0.125uA	1446mV	0.190uA
38	1405mV	0.289uA	1433mV	0.116uA
39	1476mV	0.293uA	1463mV	0.142uA
40	1360mV	0.102uA	1460mV	0.299uA
41	1495mV	0.307uA	1513mV	0.162uA
42	1518mV	0.114uA	1336mV	0.069uA
43	1441mV	0.160uA	1336mV	0.254uA
44	1427mV	0.123uA	1378mV	0.302uA
45	1325mV	0.179uA	1334mV	0.107uA
46	1430mV	0.269uA	1509mV	0.141uA
47	1381mV	0.198uA	1359mV	0.143uA
48	1370mV	0.194uA	1385mV	0.305uA
49	1335mV	0.078uA	1297mV	0.138uA
50	1291mV	0.139uA	1406mV	0.158uA
51	1421mV	0.200uA	1302mV	0.253uA
52	1498mV	0.261uA	1411mV	0.189uA
53	1433mV	0.288uA	1400mV	0.108uA
54	1482mV	0.069uA	1401mV	0.121uA
55	1348mV	0.206uA	1415mV	0.178uA
56	1308mV	0.148uA	1512mV	0.256uA
57	1313mV	0.283uA	1351mV	0.261uA
58	1372mV	0.157uA	1522mV	0.214uA
59	1296mV	0.152uA	1372mV	0.132uA
60	1476mV	0.305uA	1490mV	0.054uA

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.03.11 ~ 2014.04.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
61	1434mV	0.109uA	1335mV	0.057uA
62	1360mV	0.103uA	1519mV	0.241uA
63	1368mV	0.289uA	1491mV	0.298uA
64	1424mV	0.267uA	1515mV	0.090uA
65	1463mV	0.102uA	1434mV	0.231uA
66	1462mV	0.048uA	1411mV	0.250uA
67	1299mV	0.193uA	1472mV	0.179uA
68	1433mV	0.061uA	1382mV	0.090uA
69	1391mV	0.145uA	1350mV	0.108uA
70	1459mV	0.154uA	1317mV	0.158uA
71	1478mV	0.230uA	1494mV	0.071uA
72	1495mV	0.110uA	1434mV	0.055uA
73	1356mV	0.081uA	1421mV	0.190uA
74	1356mV	0.119uA	1466mV	0.119uA
75	1441mV	0.226uA	1468mV	0.240uA
76	1490mV	0.045uA	1394mV	0.211uA
77	1406mV	0.070uA	1344mV	0.095uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.03.11 ~ 2014.04.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	1366mV	0.073uA	1315mV	0.264uA
2	1495mV	0.093uA	1295mV	0.086uA
3	1457mV	0.209uA	1338mV	0.293uA
4	1444mV	0.222uA	1372mV	0.266uA
5	1520mV	0.289uA	1509mV	0.183uA
6	1368mV	0.059uA	1452mV	0.121uA
7	1443mV	0.083uA	1379mV	0.053uA
8	1453mV	0.302uA	1355mV	0.187uA
9	1356mV	0.081uA	1400mV	0.115uA
10	1375mV	0.047uA	1500mV	0.230uA
11	1382mV	0.276uA	1421mV	0.216uA
12	1364mV	0.297uA	1369mV	0.098uA
13	1386mV	0.135uA	1497mV	0.247uA
14	1485mV	0.112uA	1496mV	0.266uA
15	1357mV	0.239uA	1361mV	0.151uA
16	1463mV	0.118uA	1482mV	0.162uA
17	1396mV	0.285uA	1423mV	0.064uA
18	1309mV	0.181uA	1305mV	0.308uA
19	1415mV	0.119uA	1522mV	0.208uA
20	1413mV	0.077uA	1450mV	0.145uA
21	1417mV	0.138uA	1397mV	0.157uA
22	1425mV	0.180uA	1395mV	0.151uA
23	1467mV	0.118uA	1397mV	0.153uA
24	1380mV	0.089uA	1473mV	0.120uA
25	1308mV	0.158uA	1495mV	0.307uA
26	1346mV	0.209uA	1489mV	0.236uA
27	1309mV	0.087uA	1340mV	0.254uA
28	1465mV	0.235uA	1516mV	0.060uA
29	1295mV	0.296uA	1374mV	0.280uA
30	1407mV	0.214uA	1468mV	0.227uA

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.03.11 ~ 2014.04.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
31	1313mV	0.116uA	1358mV	0.128uA
32	1504mV	0.180uA	1381mV	0.286uA
33	1455mV	0.050uA	1420mV	0.137uA
34	1483mV	0.181uA	1294mV	0.185uA
35	1491mV	0.215uA	1363mV	0.274uA
36	1501mV	0.114uA	1479mV	0.077uA
37	1328mV	0.128uA	1494mV	0.272uA
38	1487mV	0.209uA	1421mV	0.159uA
39	1364mV	0.268uA	1462mV	0.286uA
40	1446mV	0.244uA	1315mV	0.223uA
41	1454mV	0.294uA	1422mV	0.095uA
42	1517mV	0.191uA	1361mV	0.108uA
43	1360mV	0.075uA	1310mV	0.150uA
44	1325mV	0.146uA	1377mV	0.099uA
45	1429mV	0.189uA	1464mV	0.148uA
46	1476mV	0.211uA	1405mV	0.274uA
47	1456mV	0.205uA	1315mV	0.266uA
48	1303mV	0.230uA	1333mV	0.145uA
49	1425mV	0.306uA	1353mV	0.288uA
50	1498mV	0.161uA	1304mV	0.141uA
51	1486mV	0.237uA	1297mV	0.084uA
52	1481mV	0.231uA	1419mV	0.298uA
53	1506mV	0.055uA	1505mV	0.308uA
54	1433mV	0.242uA	1330mV	0.270uA
55	1475mV	0.280uA	1340mV	0.148uA
56	1342mV	0.197uA	1381mV	0.257uA
57	1356mV	0.159uA	1481mV	0.223uA
58	1471mV	0.092uA	1347mV	0.141uA
59	1304mV	0.179uA	1491mV	0.165uA
60	1505mV	0.095uA	1385mV	0.184uA

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2014.03.11 ~ 2014.04.23
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
61	1442mV	0.210uA	1450mV	0.148uA
62	1336mV	0.161uA	1300mV	0.280uA
63	1381mV	0.070uA	1330mV	0.175uA
64	1504mV	0.058uA	1340mV	0.129uA
65	1423mV	0.063uA	1496mV	0.227uA
66	1394mV	0.090uA	1313mV	0.150uA
67	1291mV	0.091uA	1517mV	0.067uA
68	1462mV	0.083uA	1469mV	0.283uA
69	1361mV	0.235uA	1355mV	0.147uA
70	1384mV	0.285uA	1431mV	0.071uA
71	1455mV	0.112uA	1515mV	0.128uA
72	1478mV	0.111uA	1346mV	0.071uA
73	1373mV	0.172uA	1389mV	0.175uA
74	1293mV	0.151uA	1300mV	0.168uA
75	1446mV	0.230uA	1392mV	0.132uA
76	1398mV	0.231uA	1353mV	0.126uA
77	1443mV	0.205uA	1456mV	0.127uA

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

Solderability Test Data

Report No : T140430-021
Part No : HER207G
Test Equipment: JUNO Test System DTS-1000
Test Condition : VF<1850mV@IF=2A, IR<5uA@VR=1000V
Test Condition: 270℃ ± 5℃, 7 Sec ± 2Sec
Test Date: 2014.04.28 ~ 2014.04.28
Test Standard : JESD22 STANDER Method-A106
Operator: Leo Hsia

Test Result: PASS

	Before		After	
No	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	1393mV	0.174uA	1461mV	0.092uA
2	1315mV	0.283uA	1294mV	0.231uA
3	1502mV	0.145uA	1497mV	0.276uA
4	1376mV	0.157uA	1369mV	0.237uA
5	1496mV	0.157uA	1294mV	0.148uA
6	1410mV	0.175uA	1496mV	0.268uA
7	1479mV	0.131uA	1316mV	0.087uA
8	1520mV	0.071uA	1406mV	0.242uA
9	1467mV	0.196uA	1515mV	0.206uA
10	1463mV	0.310uA	1325mV	0.195uA

Made By: Leo Hsia

Approval: Peter Yang

簽名有效

For Question,
Please Contact with SGS
www.tw.sgs.com

Test Report

No. : CE/2014/42772A Date : 2014/04/18 Page : 1 of 14

SECOS CORPORATION

CE/2014/42772A

8F, NO. 33, LANE 155, SEC. 3, BEI-SHEN RD., SHEN KENG DIST., NEW TAIPEI CITY, TAIWAN

The following sample(s) was/were submitted and identified by/on behalf of the applicant as :

Sample Description	:	RECTIFIER(NON GREEN COMPOUND)
Style/Item No.	:	DO-15, DO-27, DO-35, DO-41, DO-201, R-1, R-6, R7 SERIES
Sample Receiving Date	:	2014/04/14
Testing Period	:	2014/04/14 TO 2014/04/18

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Test Result(s) : Please refer to next page(s).

Troy Ch
Signed
SGS TA
Chemical Laboratory – Taipei

SECOS CORPORATION *CE/2014/42772A*
8F, NO. 33, LANE 155, SEC. 3, BEI-SHEN RD., SHEN KENG DIST., NEW TAIPEI CITY, TAIWAN

Test Result(s)

PART NAME No.1 : BLACK BODY
PART NAME No.2 : PLATING LAYER OF SILVER COLORED METAL PIN
PART NAME No.3 : BASE MATERIAL OF SILVER COLORED METAL PIN
PART NAME No.4 : SILVER COLORED METAL PIN (INCLUDING THE PLATING LAYER)

Test Item(s)	Unit	Method	MDL	Result			
				No.1	No.2	No.3	No.4
Cadmium (Cd)	mg/kg	With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.	---	n.d.	---
	mg/kg	IEC 62321-5: 2013 application of modified digestion by surface etching and performed by ICP-AES.	2	---	n.d.	---	---
Lead (Pb)	mg/kg	With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	4130	---	n.d.	---
	mg/kg	IEC 62321-5: 2013 application of modified digestion by surface etching and performed by ICP-AES.	2	---	20	---	---
Mercury (Hg)	mg/kg	With reference to IEC 62321-4: 2013 and performed by ICP-AES.	2	n.d.	---	n.d.	---
	mg/kg	IEC 62321-4: 2013 application of modified digestion by surface etching and performed by ICP-AES.	2	---	n.d.	---	---
Hexavalent Chromium Cr(VI)	mg/kg	With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.	---	---	---
	**	With reference to IEC 62321: 2008 and performed by Boiling water extraction Method.#	#	---	Negative	Negative	---
Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified (α- HBCDD, β- HBCDD, γ- HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	With reference to IEC 62321: 2008 method. Analysis was performed by GC/MS.	5	n.d.	---	---	n.d.

SECOS CORPORATION *CE/2014/42772A*
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Test Item(s)	Unit	Method	MDL	Result			
				No.1	No.2	No.3	No.4
BBP (Benzyl butyl phthalate) (CAS No.: 85-68-7)	%	With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.	---	---	n.d.
DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	%	With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.	---	---	n.d.
DEHP (Di- (2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	%	With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.	---	---	n.d.
Perfluorooctane sulfonates (PFOS-Acid, Metal Salt, Amide)	mg/kg	With reference to US EPA 3550C: 2007. Analysis was performed by LC/MS.	10	n.d.	---	n.d.	---
	µg/m²	With reference to US EPA 3550C: 2007. Analysis was performed by LC/MS.	1	---	n.d.	---	---
PFOA (CAS No.: 335-67-1)	mg/kg	With reference to US EPA 3550C: 2007. Analysis was performed by LC/MS.	10	n.d.	---	n.d.	---
	µg/m²	With reference to US EPA 3550C: 2007. Analysis was performed by LC/MS.	1	---	n.d.	---	---
Halogen							
Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.	---	---	n.d.
Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC.	50	108	---	---	n.d.
Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC.	50	5720	---	---	n.d.
Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.	---	---	n.d.

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Test Item(s)	Unit	Method	MDL	Result			
				No.1	No.2	No.3	No.4
Sum of PBBs	mg/kg	With reference to IEC 62321: 2008 and performed by GC/MS.	-	n.d.	n.d.	n.d.	---
Monobromobiphenyl	mg/kg		5	n.d.	n.d.	n.d.	---
Dibromobiphenyl	mg/kg		5	n.d.	n.d.	n.d.	---
Tribromobiphenyl	mg/kg		5	n.d.	n.d.	n.d.	---
Tetrabromobiphenyl	mg/kg		5	n.d.	n.d.	n.d.	---
Pentabromobiphenyl	mg/kg		5	n.d.	n.d.	n.d.	---
Hexabromobiphenyl	mg/kg		5	n.d.	n.d.	n.d.	---
Heptabromobiphenyl	mg/kg		5	n.d.	n.d.	n.d.	---
Octabromobiphenyl	mg/kg		5	n.d.	n.d.	n.d.	---
Nonabromobiphenyl	mg/kg		5	n.d.	n.d.	n.d.	---
Decabromobiphenyl	mg/kg		5	n.d.	n.d.	n.d.	---
Sum of PBDEs	mg/kg		-	n.d.	n.d.	n.d.	---
Monobromodiphenyl ether	mg/kg		5	n.d.	n.d.	n.d.	---
Dibromodiphenyl ether	mg/kg		5	n.d.	n.d.	n.d.	---
Tribromodiphenyl ether	mg/kg		5	n.d.	n.d.	n.d.	---
Tetrabromodiphenyl ether	mg/kg		5	n.d.	n.d.	n.d.	---
Pentabromodiphenyl ether	mg/kg		5	n.d.	n.d.	n.d.	---
Hexabromodiphenyl ether	mg/kg		5	n.d.	n.d.	n.d.	---
Heptabromodiphenyl ether	mg/kg		5	n.d.	n.d.	n.d.	---
Octabromodiphenyl ether	mg/kg		5	n.d.	n.d.	n.d.	---
Nonabromodiphenyl ether	mg/kg		5	n.d.	n.d.	n.d.	---
Decabromodiphenyl ether	mg/kg		5	n.d.	n.d.	n.d.	---

Note：

1. mg/kg = ppm；0.1wt% = 1000ppm
2. n.d. = Not Detected
3. MDL = Method Detection Limit
4. " - " = Not Regulated
5. "---" = Not Conducted
6. ** = Qualitative analysis (No Unit)
7. # = a. Positive means the presence of CrVI on the tested areas
   b. Negative means the absence of CrVI on the tested areas
   The detected concentration in boiling-water-extraction solution is equal or greater than 0.02 mg/kg with 50 cm² tested areas.

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PFOS Reference Information : POPs - (EU) 757/2010

Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above 1μg/m².

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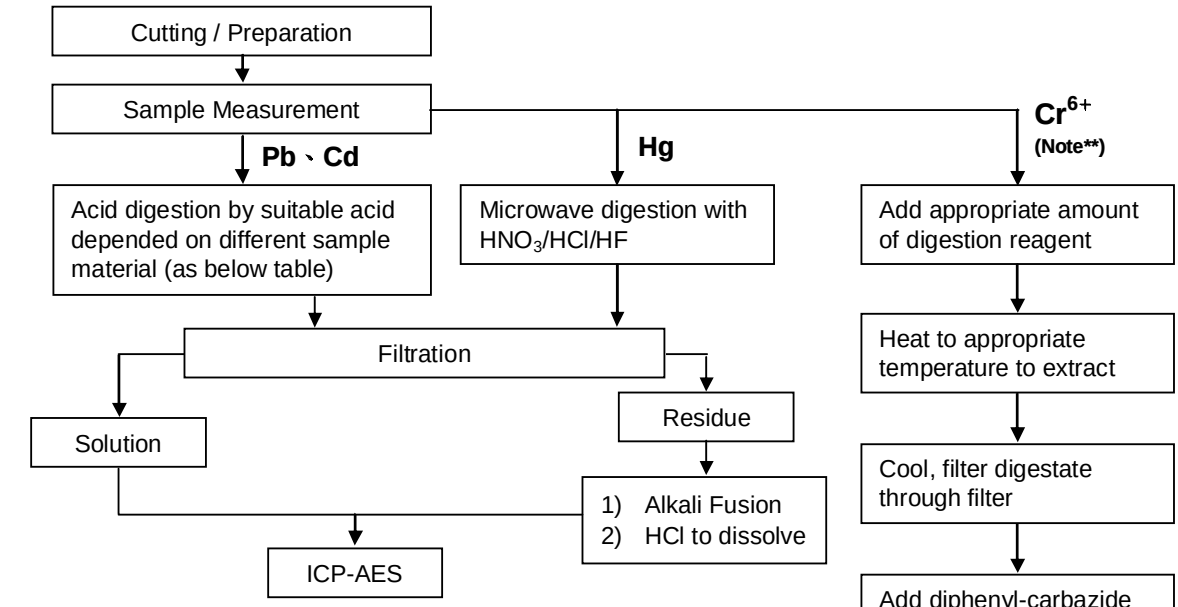
No.1, 3

1) These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr^{6+} test method excluded)
2) Name of the person who made measurement: Climbgreat Yang
3) Name of the person in charge of measurement: Troy Chang



Sample Material	Digestion Acid
Steel, copper, aluminum, solder	Aqua regia, HNO_3, HCl, HF, H_2O_2
Glass	HNO_3/HF
Gold, platinum, palladium, ceramic	Aqua regia
Silver	HNO_3
Plastic	H_2SO_4, H_2O_2, HNO_3, HCl
Others	Added appropriate reagent to total digestion

Note (For IEC 62321)**
(1) For non-metallic material, add alkaline digestion reagent and heat to 90~95℃.
(2) For metallic material, add pure water and heat to boiling.

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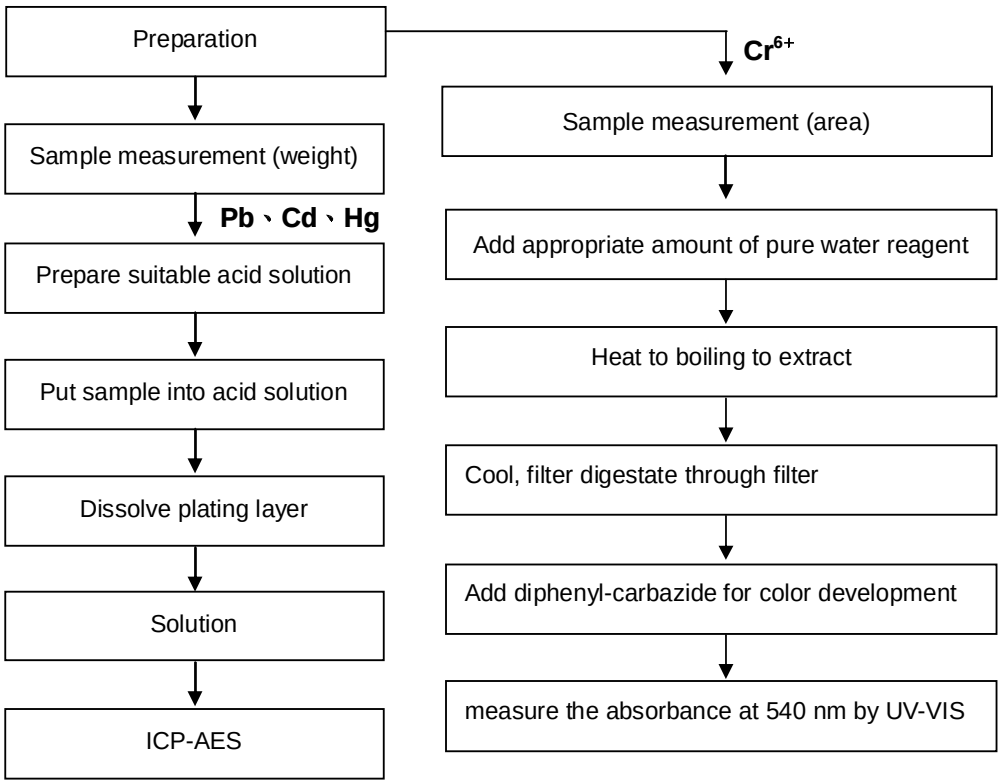
No.2

The plating layer of samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr^{6+} test method excluded)

- Name of the person who made measurement: Climbgreat Yang
- Name of the person in charge of measurement: Troy Chang

Flow Chart of Stripping method for metal analysis



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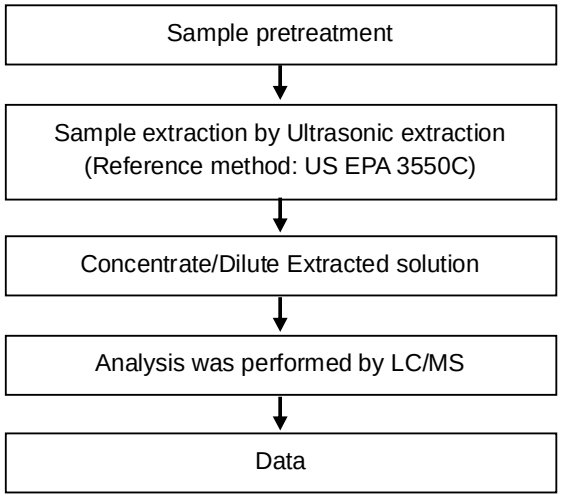
PFOA/PFOS analytical flow chart of Ultrasonic extraction (LC/MS) procedure

- Name of the person who made measurement: Roman Wong
- Name of the person in charge of measurement: Troy Chang



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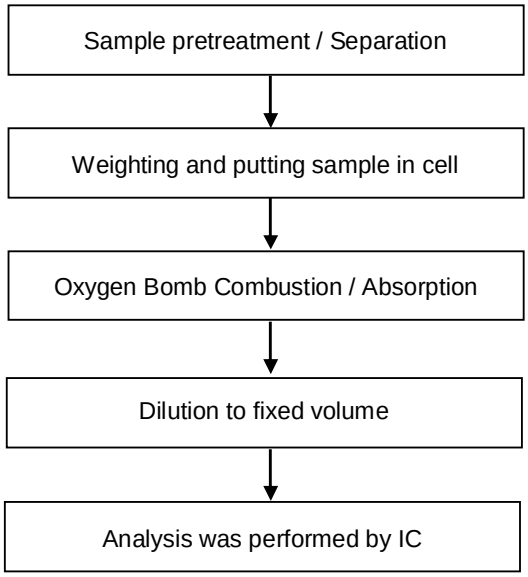
Analytical flow chart of halogen content

- Name of the person who made measurement: Rita Chen
- Name of the person in charge of measurement: Troy Chang



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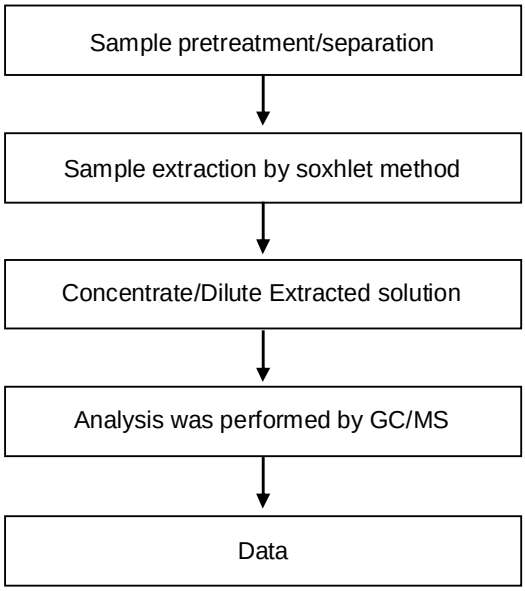
Analytical flow chart of phthalate content

- Name of the person who made measurement: Roman Wong
- Name of the person in charge of measurement: Troy Chang



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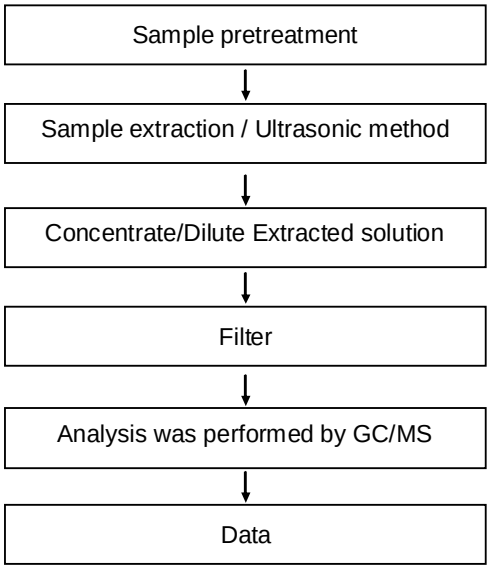
HBCDD analytical flow chart

- Name of the person who made measurement: Roman Wong
- Name of the person in charge of measurement: Troy Chang



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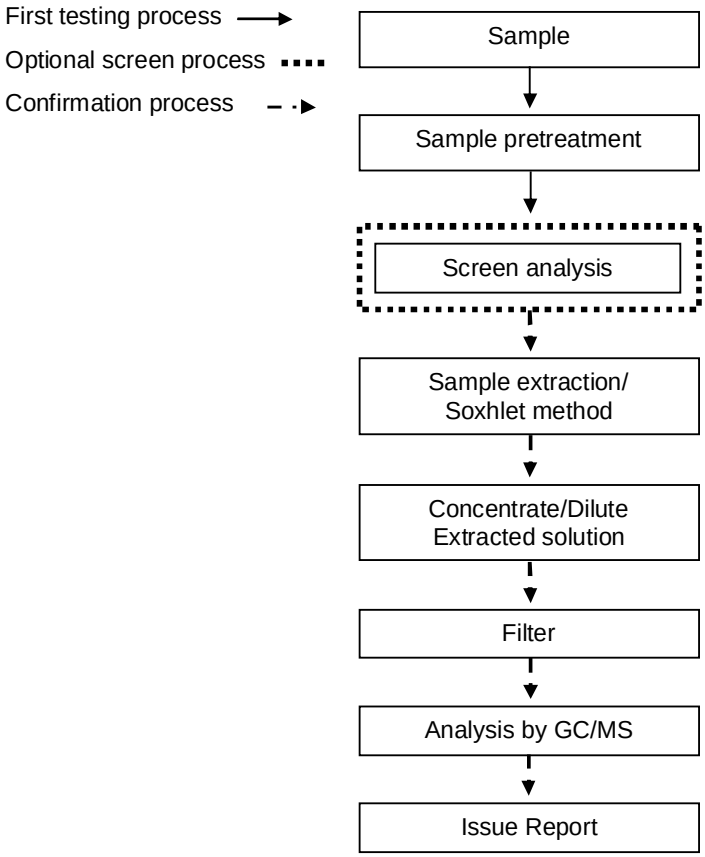
PBB/PBDE analytical FLOW CHART

- Name of the person who made measurement: Roman Wong
- Name of the person in charge of measurement: Troy Chang



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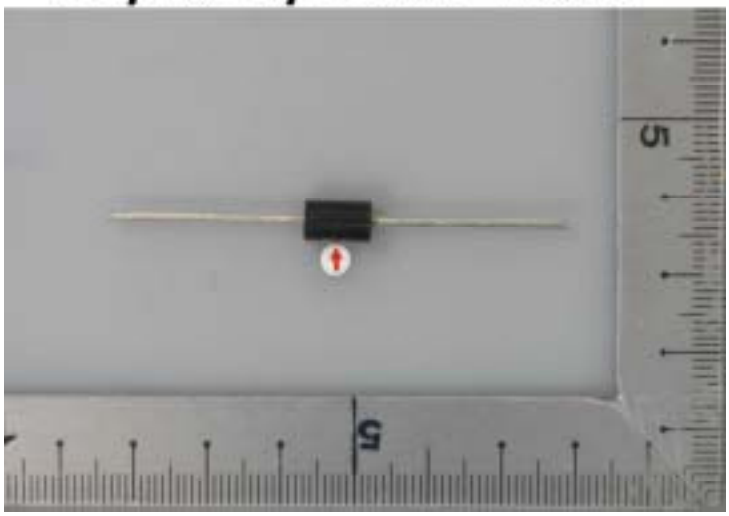
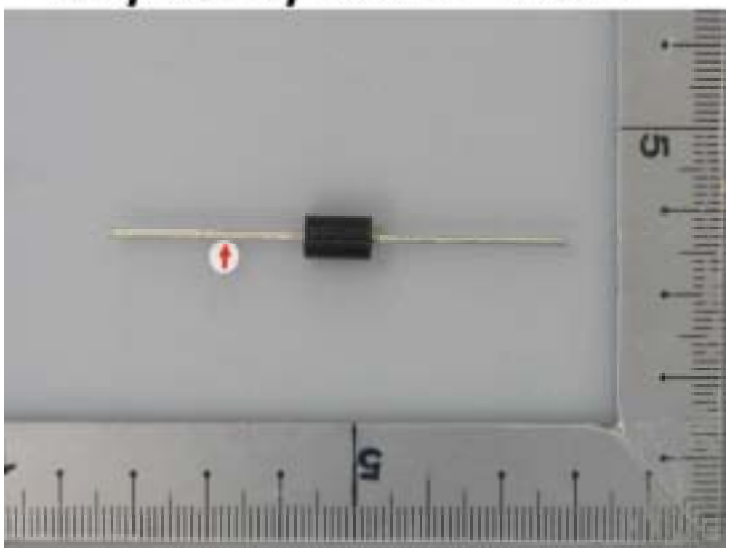
*** The tested sample / part is marked by an arrow if it's shown on the photo. ***

CE/2014/42772 NO.1



CE/2014/42772 NO.2



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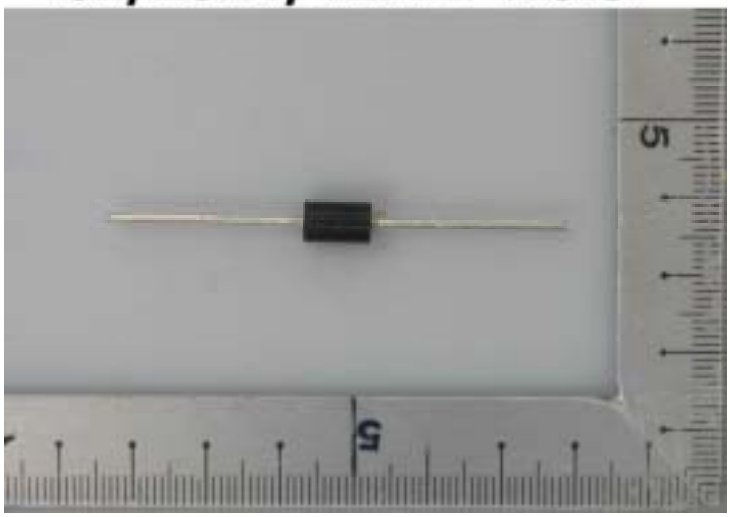
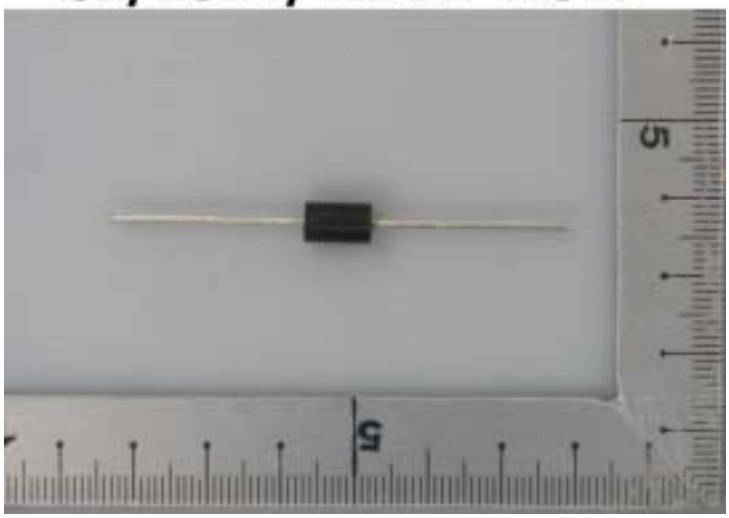
CE/2014/42772 NO.3



CE/2014/42772 NO.4



** End of Report **